MSKSEMI 美森科













ESD

15

TSS

MOV

GDT

 PLED

AOD409-MS

Product specification





General Description

These P-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

BVDSS	RDSON	ID
-60V	38mΩ	-25A

Features

- -60V,-25A, RDS(ON) $38m\Omega$ @VGS = -10V
- Improved dv/dt capability
- Fast switching
- Green Device Available

Applications

- Networking
- Load Switch
- LED applications

Reference News

PACKAGE OUTLINE	P-Channel MOSFET	Marking
TO-252	O O O O O O O O O O O O O O O O O O O	MSKSEMI AOD409

Absolute Maximum Ratings (TC=25℃unless otherwise noted)

Symbol	Parameter	Rating	Units
Vos	Drain-Source Voltage	-60	V
Vgs	Gate-Source Voltage	±20	V
lo	Drain Current - Continuous (Tc=25℃)	-25	Α
lD	Drain Current - Continuous (Tc=100℃)	-16	Α
Ірм	Drain Current - Pulsed¹	-100	Α
D-	Power Dissipation (Tc=25°C)	72	W
PD	Power Dissipation - Derate above 25°C	0.578	W/℃
Тѕтс	Storage Temperature Range	-55 to 150	$^{\circ}$
TJ	Operating Junction Temperature Range	-55 to 150	${\mathbb C}$

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		62	°C/W
Rejc	Thermal Resistance Junction to Case		1.73	°C/W



Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	Vgs=0V , Ip=-250uA	-60		-	٧
lpss	Drain-Source Leakage Current	V _{DS} =-60V , V _{GS} =0V , T _J =25℃			-1	uA
1033	Drain coares coarage carrein	V _{DS} =-48V , V _{GS} =0V , T _J =125℃			-10	uA
Igss	Gate-Source Leakage Current	Vgs=±20V , Vps=0V			±100	nA

On Characteristics

RDS(ON)	Static Drain-Source On-Resistance	Vgs=-10V , Ip=-8A		38	48	mΩ
		Vgs=-4.5V , ID=-6A		46	60	mΩ
V _{GS(th)}	Gate Threshold Voltage	Vgs=Vds , Id =-250uA	-1.0	-1.6	-2.5	V
gfs	Forward Transconductance	V _{DS} =-10V , Is=-3A		11		S

Dynamic and switching Characteristics

Dynamic a	nu switching characteristics			
Qg	Total Gate Charge ^{2, 3}		 19	
Qgs	Gate-Source Charge ^{2,3}	Vds=-30V , Vgs=-10V , Id=-10A	 2.5	 nC
Qgd	Gate-Drain Charge ^{2, 3}		 4.3	
T _{d(on)}	Turn-On Delay Time ^{2,3}		 25	
Tr	Rise Time ^{2, 3}	VDD=-30V , VGS=-10V ,	 58	
Td(off)	Turn-Off Delay Time ^{2, 3}	R _G =25Ω l _D =-10A	 65	 ns
Tf	Fall Time ^{2, 3}		 35	
Ciss	Input Capacitance		 1200	
Coss	Output Capacitance	V _{DS} =-30V , V _{GS} =0V , F=1MHz	 85	 pF
Crss	Reverse Transfer Capacitance		 60	
Rg	Gate resistance	Vgs=0V, Vds=0V, F=1MHz	 14	 Ω

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V _G =V _D =0V , Force Current			-25	Α
lsм	Pulsed Source Current	Vo Vb VV , I oloo Gallent			-50	Α
VsD	Diode Forward Voltage	Vgs=0V , Is=-1A , TJ=25℃			-1.2	V

Note

- 1.Repetitive Rating: Pulsed width limited by maximum junction temperature.
- $2.V_{DD}\text{=}25V, V_{GS}\text{=}10V, L\text{=}0.1 mH, I_{AS}\text{=}11A., R_{G}\text{=}25\Omega, Starting \ T_{J}\text{=}25^{\circ}C.$
- 3.The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%.
- 4. Essentially independent of operating temperature.



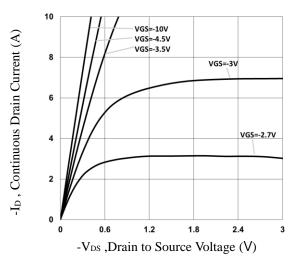


Fig.1 Typical Output Characteristics

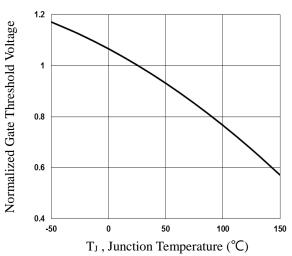


Fig.3 Normalized V_{th} vs. T_J

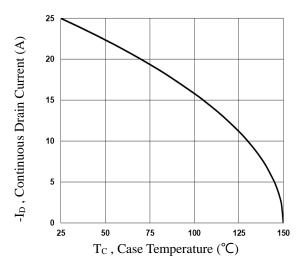


Fig.5 Continuous Drain Current vs. TJ

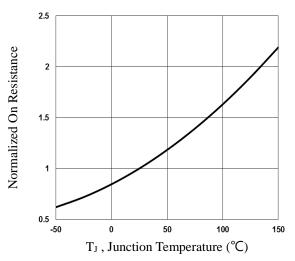


Fig.2 Normalized RDSON vs. TJ

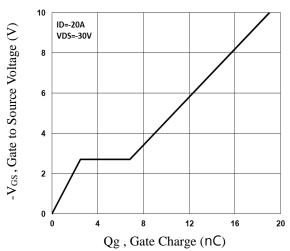


Fig.4 Gate Charge Waveform

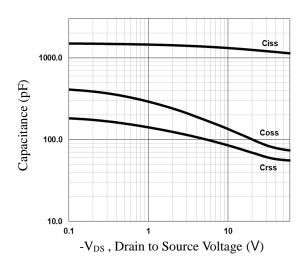


Fig.6 Capacitance Characteristics



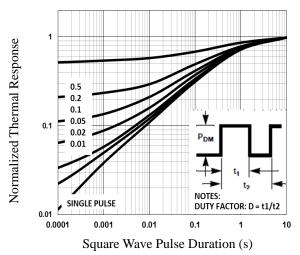


Fig.7 Normalized Transient Impedance

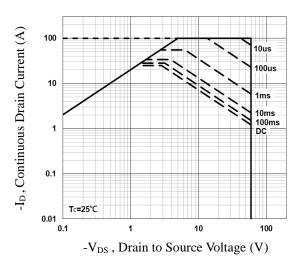
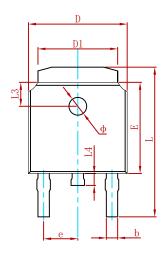
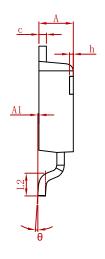


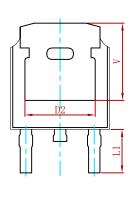
Fig.8 Maximum Safe Operation Area



PACKAGE MECHANICAL DATA

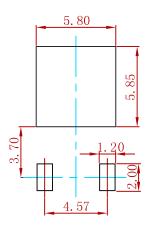






Ol	Dimensions	Dimensions In Millimeters		s In Inches
Symbol	Min.	Max.	Min.	Max.
Α	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.635	0.770	0.025	0.030
С	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830	REF.	0.190	REF.
E	6.000	6.200	0.236	0.244
е	2.186	2.386	0.086	0.094
L	9.712	10.312	0.382	0.406
L1	2.900	REF.	0.114	REF.
L2	1.400	1.700	0.055	0.067
L3	1.600	REF.	0.063	REF.
L4	0.600	1.000	0.024	0.039
Ф	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.250	REF.	0.207	REF.

Suggested Pad Layout



Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

REELSPECIFICATION

P/N	PKG	QTY
AOD409-MS	TO-252	2500



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